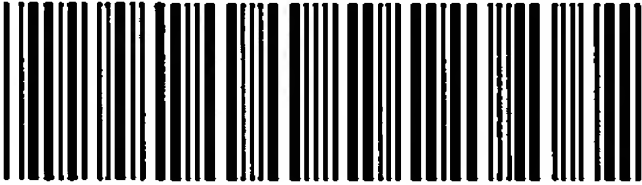


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/660,033	BEUKEMA ET AL.	
	Examiner	Art Unit	
	Alan S. Chen	2182	

SEARCHED			
Class	Subclass	Date	Examiner
710	53	2/9/2006	ASC
↓	54		
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	57		
709	200		
↓	213	↓	↓

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT	2/9/2006	ASC